

(12)

United States Design Patent

Lee et al.

(10)

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(45)

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(54) **DIAGNOSTIC ANALYZER UNIT**

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(**) Term: **15 Years**

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(51) **LOC (14) Cl.** **24-02**

(52) **U.S. Cl.**
USPC **D24/216**

(58) **Field of Classification Search**
USPC D24/107, 108, 186, 216, 223, 224, 226,
D24/227, 231, 232; D10/81
CPC A61J 1/2086; A61J 1/2096; A61J 1/2089;
B01L 3/021; B01L 3/058; B01L 3/52;
B01L 3/5085; B01L 2200/16; B01L
3/5023; G01N 21/78; G01N 1/38; G01N
21/6428; G01N 33/50; G01N 33/49;
A61B 5/0006; A61B 5/0205; C12M
23/08; C12M 23/14; C12M 23/44; C12M
23/46; C12M 23/48; C12M 23/58
See application file for complete search history.

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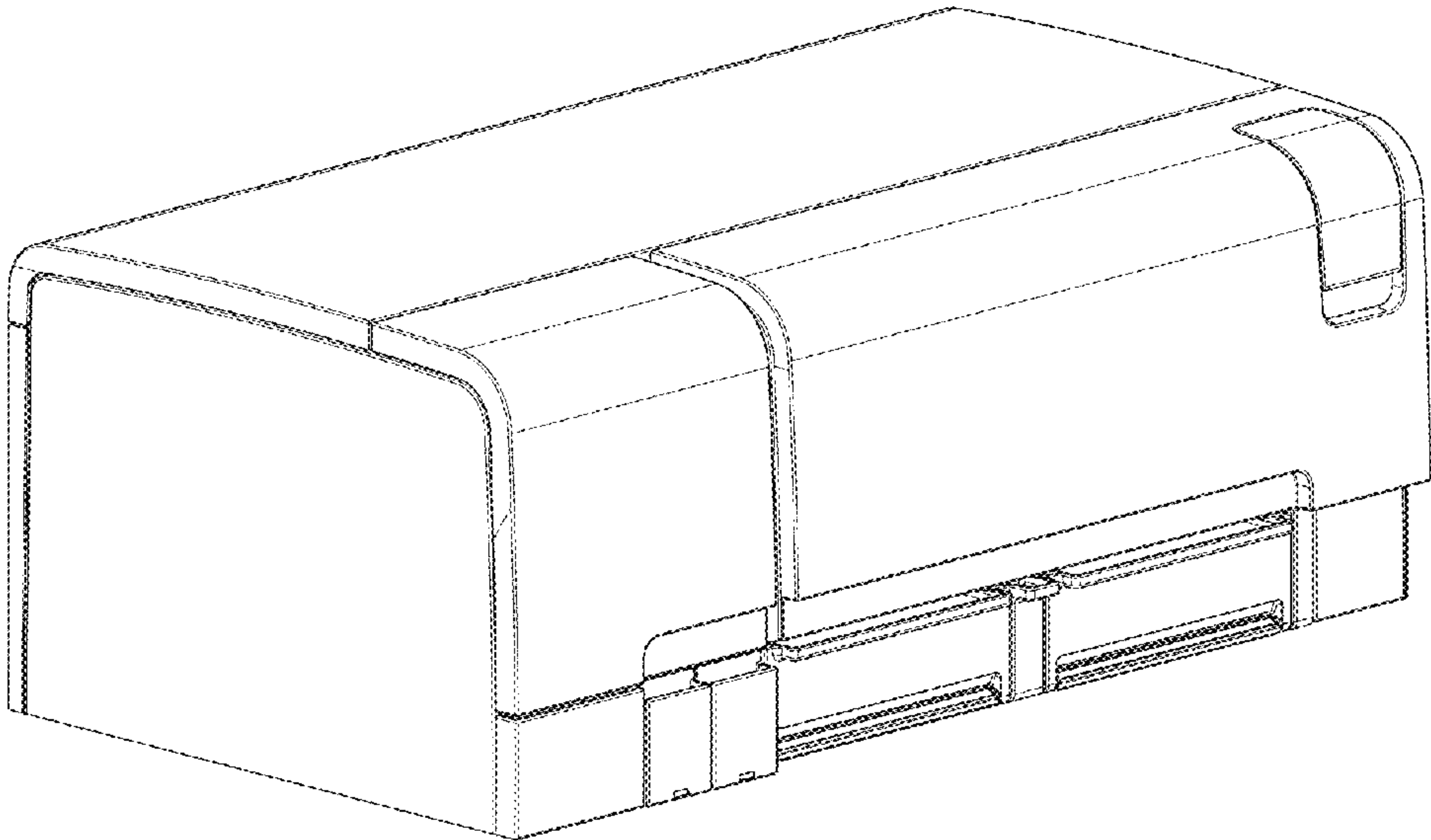
(57) **CLAIM**

The ornamental design for a diagnostic analyzer unit as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of the diagnostic analyzer unit. FIG. 2 is a front view of the diagnostic analyzer unit. FIG. 3 is a back view of the diagnostic analyzer unit. FIG. 4 is a first side view of the diagnostic analyzer unit. FIG. 5 is a second side view of the diagnostic analyzer unit. FIG. 6 is a top view of the diagnostic analyzer unit; and, FIG. 7 is a bottom view of the diagnostic analyzer unit. In the drawings, the equal-length broken lines depict portions of the diagnostic analyzer unit that form no part of the claimed design.

1 Claim, 7 Drawing Sheets



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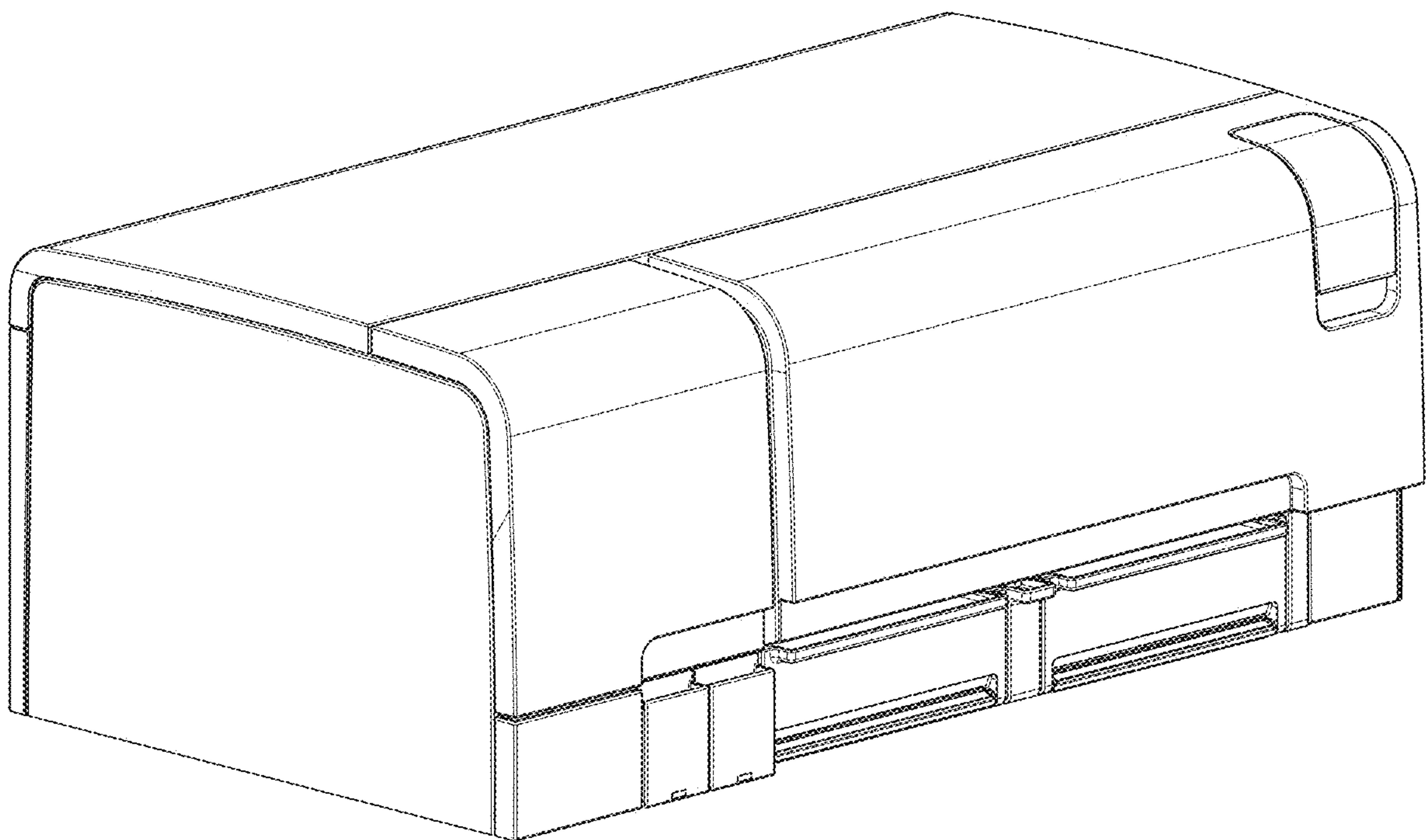


FIG. 1

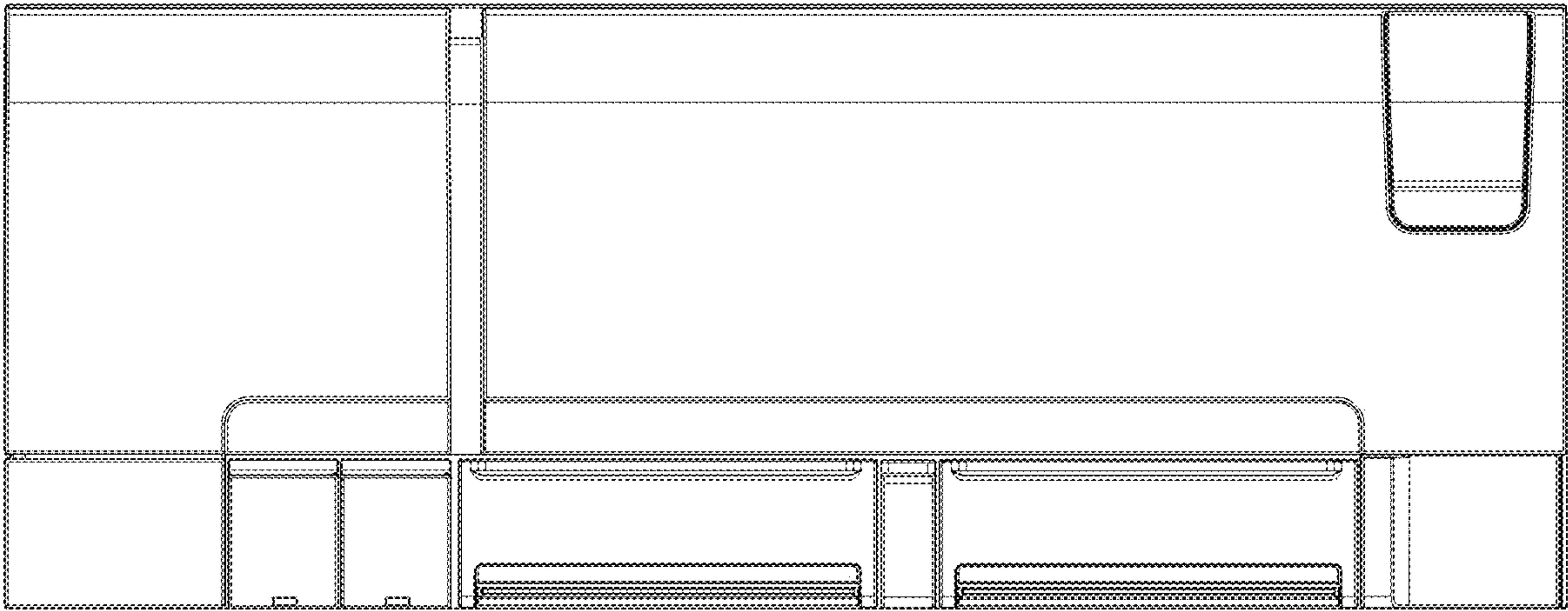


FIG. 2

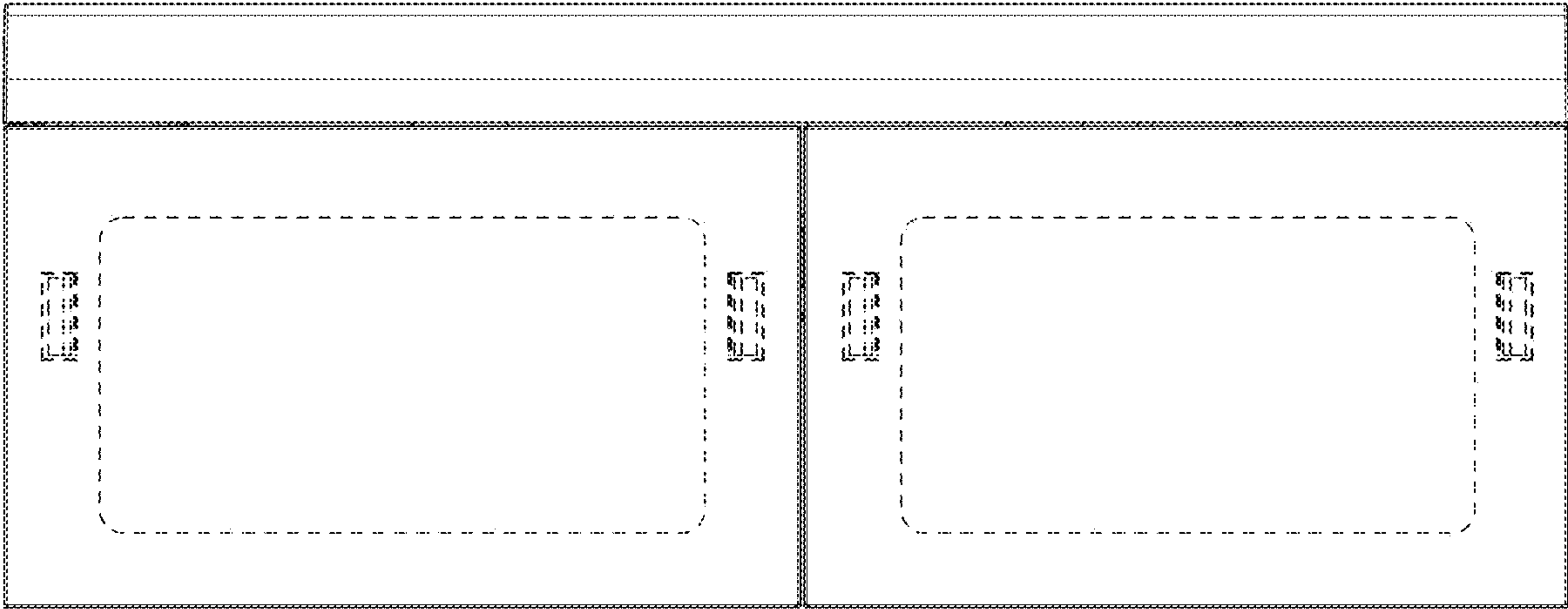


FIG. 3

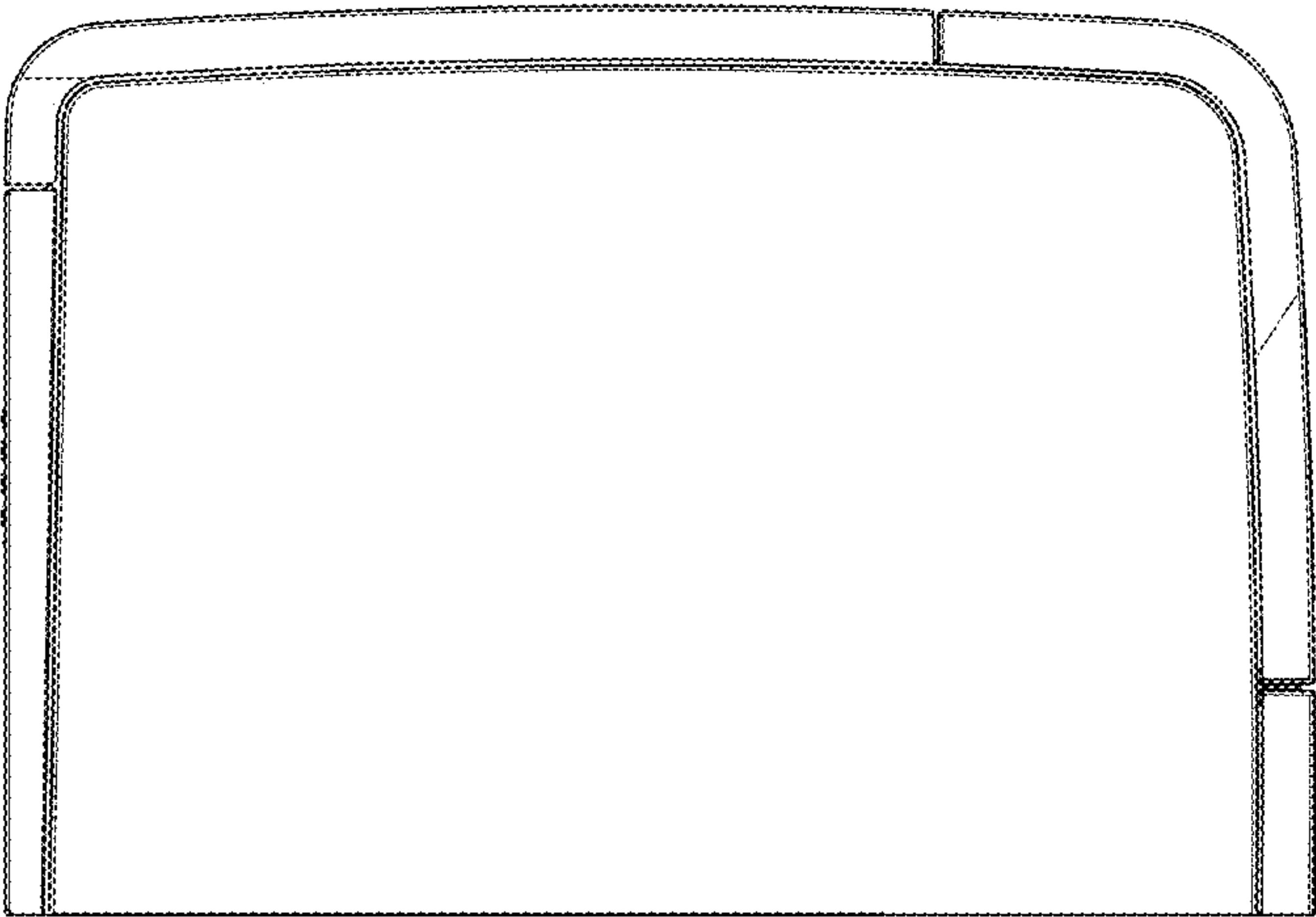


FIG. 4

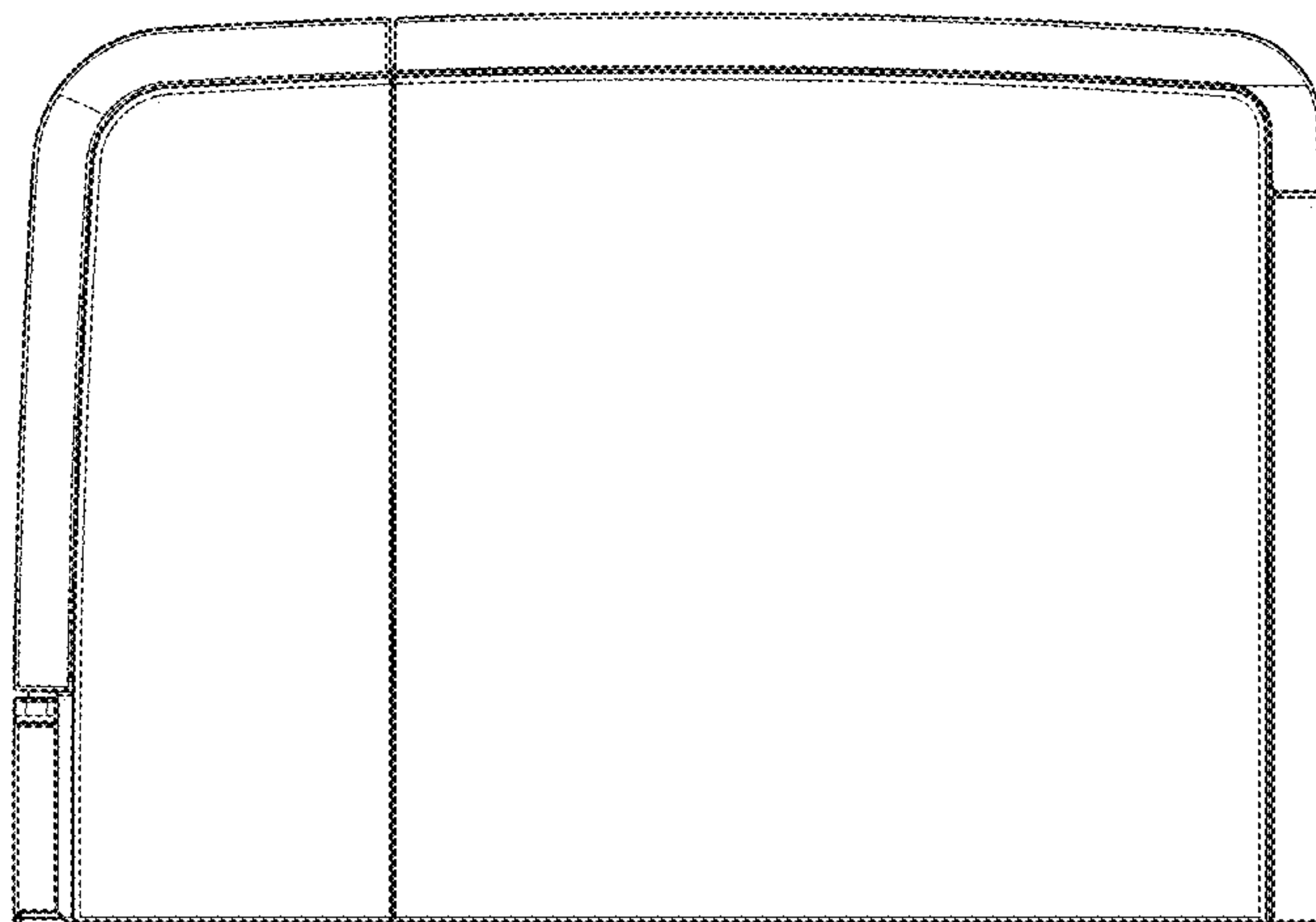


FIG. 5

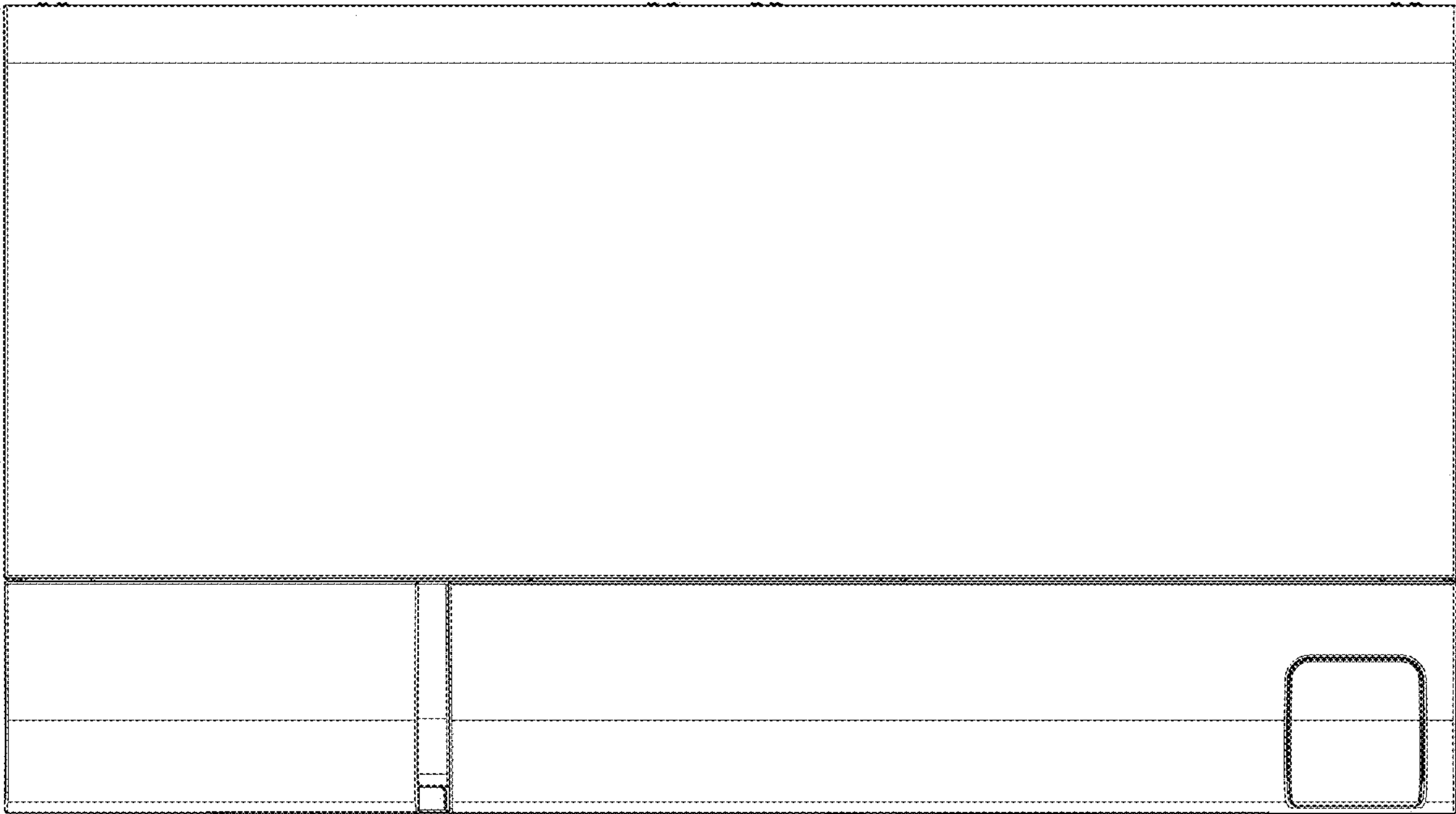


FIG. 6

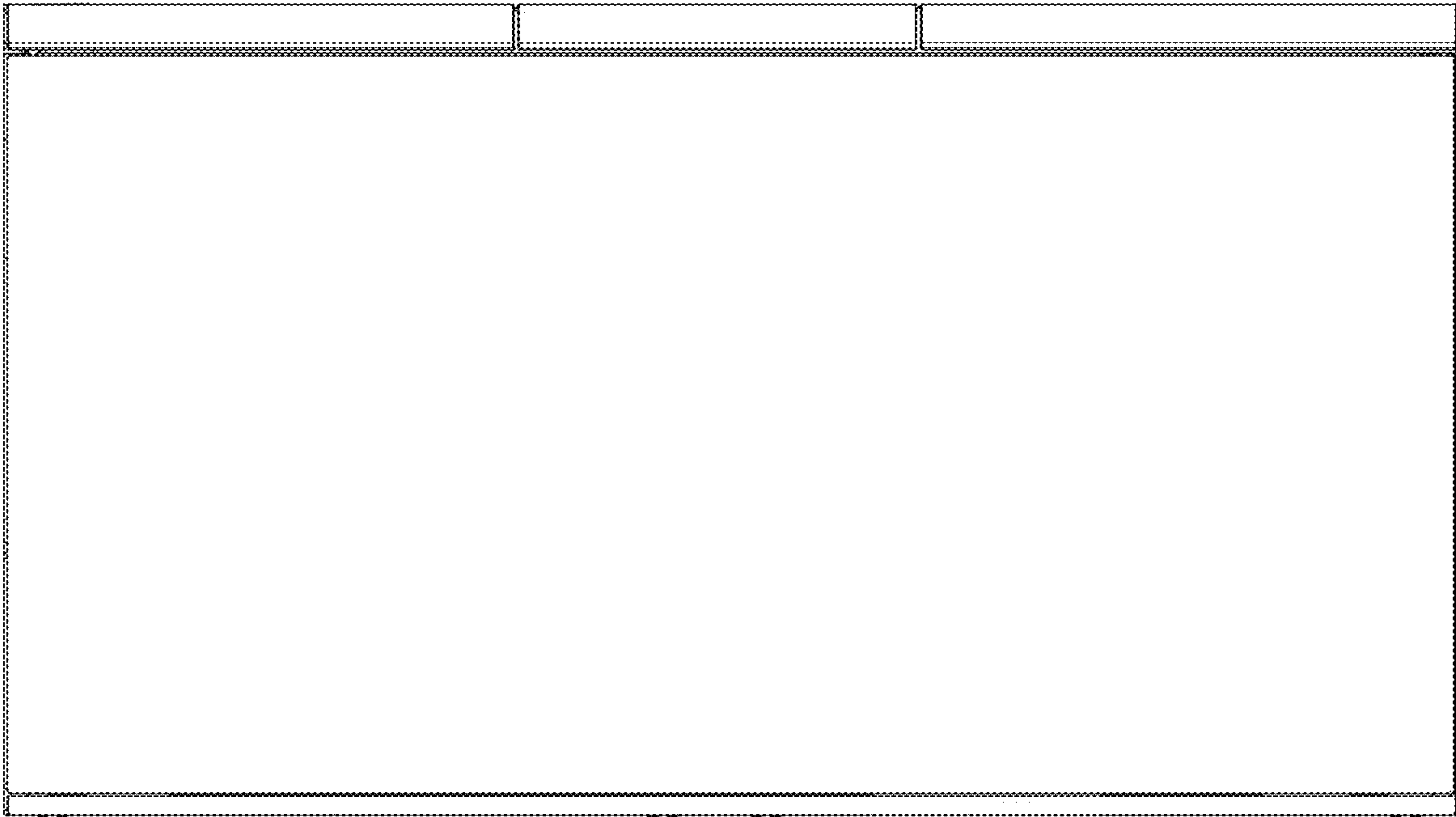


FIG. 7